

ORGANIZATION

VUV BEAMLINE GUIDE

Beam line	Research Program	Energy (eV)	Affiliation	Local Contact	Spokesperson
U1A	SEXAFS, ARUPS, XPS	100-1000	Exxon	M Sansone 516-344-3265 516-344-5759	P Stevens 908-730-2584
U1B	(Conceptual)		Exxon	M Sansone 516-344-3265 516-344-5759	P Stevens 908-730-2584
U2A	IR	6 meV-3 eV	Carnegie Inst. Wash	R Lu 516-344-5502 202-686-2410	R Hemley 516-344-5917 202-686-2410x2465
U2B	IR Microscopy, Spectroscopy	6 meV-0.6 eV	Albert Einstein	L Miller 516-344-5609 516-344-2091	M Chance 516-344-5787 718-430-4136/2894
U3A	Detector and system calibration; meas. of material optical const.; spectrometric properties	70-2100	Smiths Astro Obs Bechtel Nevada Los Alamos Natl Lab Pacific NW Natl Lab	A Burek 516-344-5521 516-344-5503	R Blake 516-344-5708 505-466-0566
U3B	(Conceptual)				
U3C	Photoelectron spect.; exp. system and detector calibrations	40-1600	Los Alamos Natl Lab Sandia Natl Lab SFA, Inc	M Sagurton 516-344-5708	R Bartlett 516-344-5708 505-667-5923
U4A	Photoemission spectroscopy to study electronic structure in solids, surfaces	15-200	Boston U No Carolina St U BNL-NSLS Rutgers U	516-344-5504	K Smith 516-344-5504 617-353-6117
U4B	Soft x-ray and/VUV photoemission spectroscopy and photo absorption	20-1200	Naval Res Lab BNL-NSLS SRRC	J Park 516-344-7290 516-344-4744	Y Idzerda 202-767-4481

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U4IR	Grazing incid. Reflectivity in UHV; transmission & normal incidence reflectivity	2.5 meV-0.5 eV	BNL-NSLS	G Williams 516-344-3634 516-344-7529	G Williams 516-344-3634 516-344-7529
U5	Diagnostic instrument monitors beam parameters during operations and machine studies		BNL-NSLS	R Nawrocky 516-344-5505 516-344-4449	R Nawrocky 516-344-5505 516-344-4449
U5UA	Spin polarized angle-resolved ultraviolet photoemission	10-200	BNL-NSLS BNL-Physics ANL U of Texas	E Vescovo 516-344-5505 516-344-7399	E Vescovo 516-344-5505 516-344-7399
U6	(Available)				
U7A	XPS and XAS on surface and in bulk, under vacuum and atm.P	150-1200	BNL-Physics BNL-Chemistry Dow Chem NIST U of Michigan Rutgers U Texas A&M U	Q Dong 516-344-5507 516-344-5358	D Fischer 516-344-5177
U7B	Photoemission; SEXAFS	15-300	BNL-NSLS	Q Dong 516-344-5507 516-344-5358	S Hulbert 516-344-7570
U8A	ARUPS NEXAFS	10-130	UCA@Riverside	J Yarmoff 516-344-5508 909-787-5336/3537	J Yarmoff 909-787-5336/3537
U8B	ARUPS NEXAFS	10-1000	IBM	K Zhang 516-344-5508	R McFeely 914-945-2068
U8C	Zone plate monochr. evaluation; reflectivity measurements of thin films and multilayers	200-600	IBM	R McFeely 516-344-5508 914-945-2068	R McFeely 914-945-2068
U8D	(Conceptual) Scanning soft x-ray microscopy		IBM	R McFeely 516-344-5508 914-945-2068	R McFeely 914-945-2068

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U9A	(Planned) PSD measurements of UHV materials at room temperature	White Beam	BNL-NSLS	C Lanni 516-344-7766 516-344-4100	C Foerster 516-344-4754
U9B	Absorption.;CD;MCD; flores/phosphorescence spectroscopy (incl. times-res. fl.)	3-12	BNL-Biology	J Sutherland 516-344-5509 516-344-3406	J Sutherland 516-344-5509 516-344-3406
U10A	(Commissioning GU {1998} High Brightnes IR measurements on "bad metals"	6 meV-3 eV	BNL-NSLS BNL-Physics SUNY @ Stony Brook	G Carr 516-344-6220 516-344-2237	G Homes 516-344-5510 516-344-7579
U10B	IR microspectroscopy	50 meV-0.6 eV	BNL-NSLS Northrop Grumman	G Carr 516-344-5510 516-344-2237	G Williams 516-344-7529
U11	Gas phase photo-ionization and spectroscopy	5-30	BNL-DAS BNL-Biology BNL-NSLS	J Sutherland 516-344-5509 516-344-3406	B Klemm 516-344-5511 516-342-4001
U12A	Soft x-ray photoemission (SXPS); XAS; NEXAFS	100-800	Oak Ridge Natl Lab BNL-NSLS	S Hulbert 516-344-5913 516-344-7570	D Mullins 516-344-5512 423-574-2796
U12IR	IR and far-IR measurement time-resolved (pump/probe IR & far-IR spectroscopy	0.3 meV-1 eV	U of Florida BNL-NSLS	G Carr 516-344-6220 516-344-2237	D Tanner 352-392-4718
U13UA	High res VUV/soft x-ray abs and electron spectr. (incl. spin-polarized photoemission)	White Beam	BNL-NSLS	S Hulbert 516-344-5913 516-344-7570	S Hulbert 516-344-5913 516-344-7570
U13UB	UV/VUV spectroscopy; hi resol. Angle resolved photoemission of solid surf.;pump-probe GU-'98	5-30	BNL-NSLS BNL-Physics Boston U Brandeis U	S Hulbert 516-344-5513 516-344-7570	E Jensen 617-736-2865
U13UC	Interferometry	White Beam	Lucent Tech	S Spector 516-344-5513	O Wood 908-582-4457

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U14A	VUV/soft x-ray spectroscopy Auger Photo-Electron Coincidence Spectroscopy (APECS)	15-300	BNL-NSLS Rutgers U	S Hulbert 516-344-5514 516-344-5930	S Hulbert 516-344-5514 516-344-7570 R Bartynski 908-445-4839
U14B	Diagnostic Instrument: VUV Ring beam position monitoring		BNL-NSLS	J Hastings 516-344-5514 516-344-3930	J Hastings 516-344-5514 516-344-3930
U15	Soft x-ray spectroscopy (solids and gases)	300-800	BNL-NSLS SUNY@Buff SUNY@SB	A Wen 516-344-5515 516-632-7918	D Hanson 516-632-7917
U16A	(Available)				
U16B	Core level Photo-emission; soft X-ray photoabsorption spectroscopy; Auger photoelectron coincidence spectroscopy (APECS)	5-1000	BNL-NSLS	S Hulbert 516-344-5516 516-344-7570	S Hulbert 516-344-5516 516-344-7570